

Attorney's Docket No. 5308-157IP2

1762-B
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Das et al.

Serial No.: 10/045,542

Filed: October 26, 2001

For: METHOD OF FABRICATING AN OXIDE LAYER ON A SILICON
CARBIDE LAYER UTILIZING AN ANNEAL IN A HYDROGEN
ENVIRONMENT

Confirmation No.: 3570

Group Art Unit: 1762

Examiner: Michael. E. Barr

Date: November 5, 2003

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Sir:

Attached is a list of documents on form PTO-1449 together with a copy of each identified document. It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. § 1.56 and Section 609 of the MPEP.

This Information Disclosure is submitted in accordance with 37 C.F.R. § 1.97(b)(4), before the mailing of a first action after the filing of a Request for Continued Examination under 37 C.F.R. § 1.114. Therefore, no fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 50-0220.

Respectfully submitted,

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I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450 on November 5, 2003.

Traci A. Brown

FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				Attorney Docket Number 5308-157IP2		Serial No. 10/045,542	
				Applicants: Das et al.			
				Filing Date: October 26, 2001		Group 1762	
U. S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	1	5,587,870	12/24/96	Anderson et al.	361	313	
	2	5,877,045	3/2/99	Kapoor	438	151	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	3	WO99/63591	12/9/99	PCT			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
	4	Mutin, P. Herbert, "Control of the Composition and Structure of Silicon Oxycarbide and Oxynitride Glasses Derived from Polysiloxane Precursors," <i>Journal of Sol-Gel Science and Technology</i> . Vol. 14 (1999) pp. 27-38.					
	5	del Prado et al. "Full Composition Range Silicon Oxynitride Films Deposited by ECR-PECVD at Room Temperatures," <i>Thin Solid Films</i> . Vol. 343-344 (1999) p. 437-440.					
	6	Wang et al. "High Temperature Characteristics of High-Quality SiC MIS Capacitors with O/N/O Gate Dielectric," <i>IEEE Transactions on Electron Devices</i> . Vol. 47, No. 2, February 2000.					
	7	International Search Report for PCT/US02/09393 dated 10/15/03.					

 EXAMINER _____
 *EXAMINER _____

DATE CONSIDERED _____

Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.